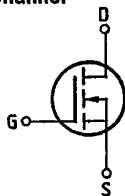


SIEMENS AKTIENGESELLSCHAFT

Main ratings

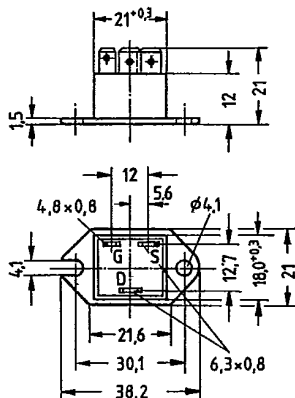
Drain-source voltage	V_{DS}	= 1000 V
Continuous drain current	I_D	= 4,2 A
Drain-source on-resistance	$R_{DS(on)}$	= 2,0 Ω

N-Channel

**Description** SIPMOS, N-channel, enhancement mode

Case Plastic package TO 238 AA with insulated metal base plate in accordance with JEDEC, compatible with TO 3; AMP plug-in connections.
Approx. weight 21 g

Type	Ordering code
BUZ 58	C67078-A1607-A2



Maximum ratings

Dimensions in mm

Description	Symbols	Ratings	Units	Conditions
Drain-source voltage	V_{DS}	1000	V	
Drain-gate voltage	V_{DGR}	1000	V	$R_{GS} = 20 \text{ k}\Omega$
Continuous drain current	I_D	4,2	A	$T_C = 25^\circ\text{C}$
Pulsed drain current	I_{Dpuls}	17	A	$T_C = 25^\circ\text{C}$
Gate-source voltage	V_{GS}	± 20	V	
Max. power dissipation	P_D	83,3	W	$T_C = 25^\circ\text{C}$
Operating and storage temperature range	T_{stg}	$-40 \dots +150$	$^\circ\text{C}$	
Isolation test voltage	V_{is}	3500	Vdc ¹⁾	$t = 1 \text{ min}$
DIN humidity category		F	—	DIN 40040
IEC climatic category		40/150/56	—	DIN IEC 68-1

Thermal resistance

Chip – case	R_{thJC}	$\leq 1,5$	K/W
-------------	------------	------------	-----

¹⁾ Isolation test voltage between drain and base plate referred to standard climate 23/50 in accordance with DIN 50014.

SIEMENS AKTIENGESELLSCHAFT

Electrical characteristics(at $T_j = 25^\circ\text{C}$ unless otherwise specified)

Description	Symbol	Characteristics			Unit	Conditions
		min.	typ.	max.		

Static ratings

Drain-source breakdown voltage	$V_{(BR) DSS}$	1000	—	—	V	$V_{GS} = 0V$ $I_D = 0,25mA$
Gate threshold voltage	$V_{GS(th)}$	2,1	3,0	4,0		$V_{DS} = V_{GS}$ $I_D = 1mA$
Zero gate voltage drain current	I_{DSS}	—	20 100	250 1000	μA	$T_j = 25^\circ\text{C}$ $T_j = 125^\circ\text{C}$ $V_{DS} = 1000V$ $V_{GS} = 0V$
Gate-source leakage current	I_{GSS}	—	10	100	nA	$V_{GS} = 20V$ $V_{DS} = 0V$
Drain-source on-resistance	$R_{DS(on)}$	—	1,7	2,0	Ω	$V_{GS} = 10V$ $I_D = 2,6A$

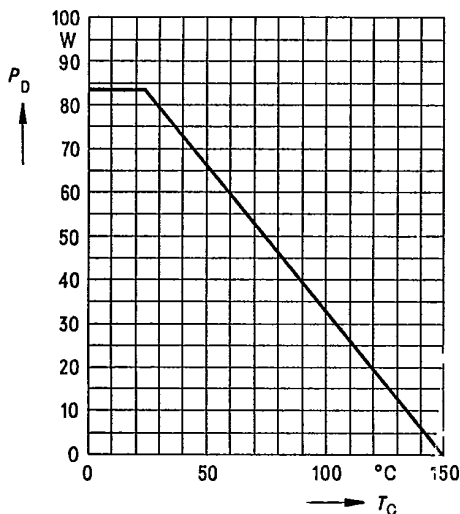
Dynamic ratings

Forward transconductance	g_{fs}	1,4	3,5	—	S	$V_{DS} = 25V$ $I_D = 2,6A$
Input capacitance	C_{iss}	—	3,9	5,0	nF	$V_{GS} = 0V$ $V_{DS} = 25V$ $f = 1MHz$
Output capacitance	C_{oss}	—	180	300	pF	
Reverse transfer capacitance	C_{rss}	—	70	120		
Turn-on time t_{on} ($t_{on} = t_{d(on)} + t_r$)	$t_{d(on)}$	—	60	90	ns	$V_{CC} = 30V$ $I_D = 2,5A$ $V_{GS} = 10V$ $R_{GS} = 50\Omega$
	t_r	—	90	140		
Turn-off time t_{off} ($t_{off} = t_{d(off)} + t_f$)	$t_{d(off)}$	—	330	430		
	t_f	—	110	140		

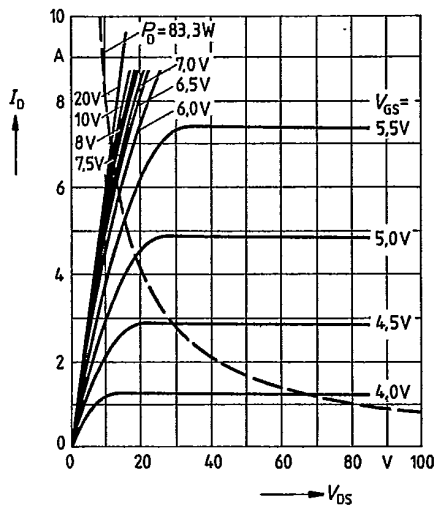
Reverse diode

Continuous reverse drain current	I_{DR}	—	—	4,2	A	$T_C = 25^\circ\text{C}$
Pulsed reverse drain current	I_{DRM}	—	—	17		
Diode forward on-voltage	V_{SD}	—	1,1	1,4	V	$I_F = 2 \times I_{DR}$ $V_{GS} = 0V, T_j = 25^\circ\text{C}$
Reverse recovery time	t_{rr}	—	2000	—	ns	$T_j = 25^\circ\text{C}$
Reverse recovery charge	Q_{rr}	—	30	—	μC	$I_F = I_{DR}$ $dI_F/dt = 100A/\mu s$ $V_R = 100V$

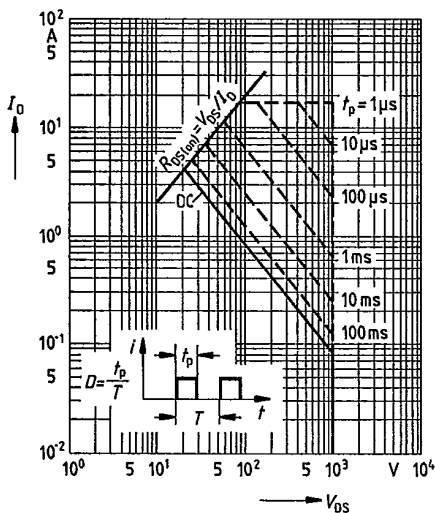
Power dissipation $P_D = f(T_C)$



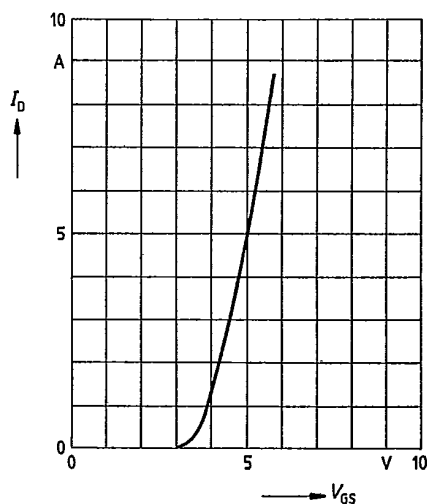
Typical output characteristics $I_D = f(V_{DS})$
parameter: 80 μ s pulse test,
 $T_J = 25^\circ\text{C}$



Safe operating area $I_D = f(V_{DS})$
parameter: $D = 0.01$, $T_C = 25^\circ\text{C}$



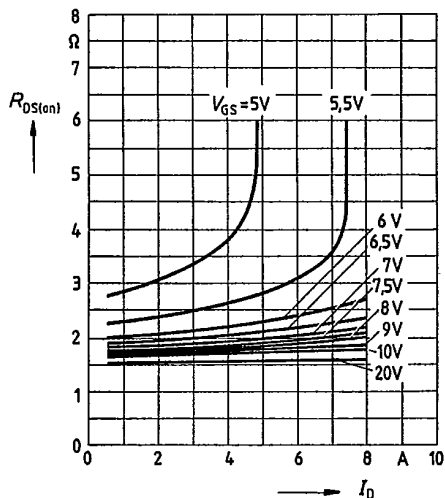
Typical transfer characteristic $I_D = f(V_{GS})$
parameter: 80 μ s pulse test,
 $V_{DS} = 25\text{V}$, $T_J = 25^\circ\text{C}$



Typical drain-source on-state resistance

$$R_{DS(on)} = f(I_D)$$

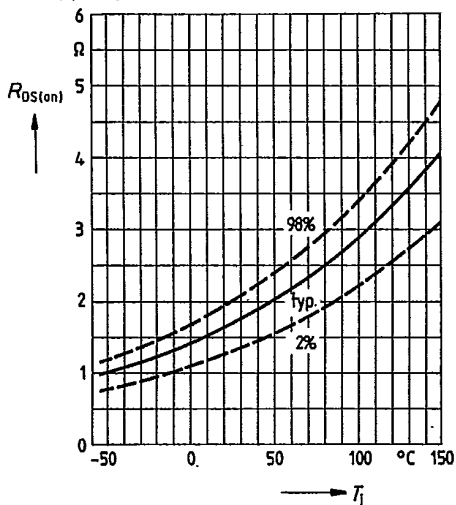
parameter: $V_{GS} = 5V$, $T_j = 25^\circ C$



Drain-source on-state resistance

$$R_{DS(on)} = f(T_j)$$

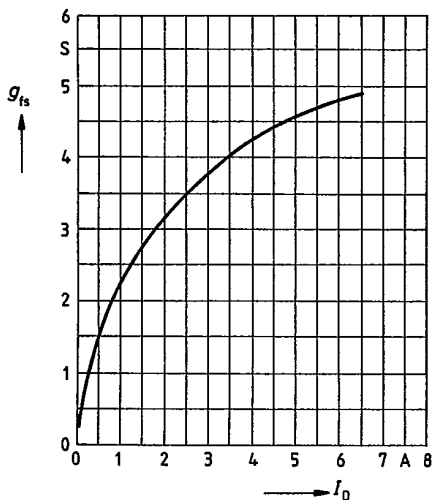
parameter: $I_D = 2.6A$, $V_{GS} = 10V$ (spread)



Typical transconductance $g_{fs} = f(I_D)$

parameter: 80 μs pulse test,

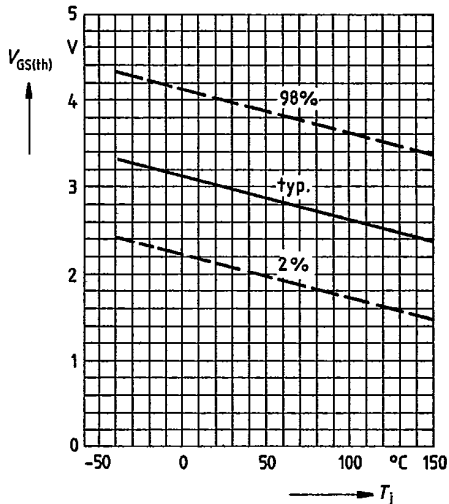
$V_{DS} = 25V$, $T_j = 25^\circ C$



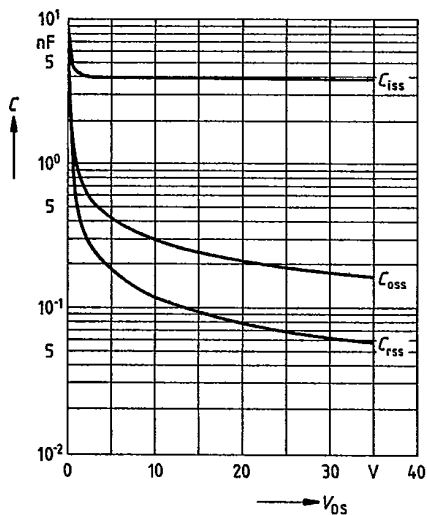
Gate threshold voltage $V_{GS(th)} = f(T_j)$

parameter: $V_{DS} = V_{GS}$, $I_D = 1mA$

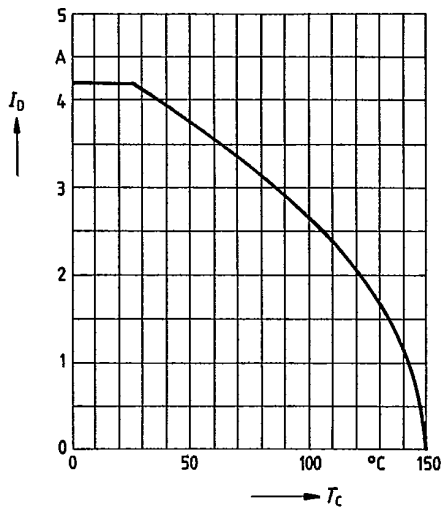
(spread)



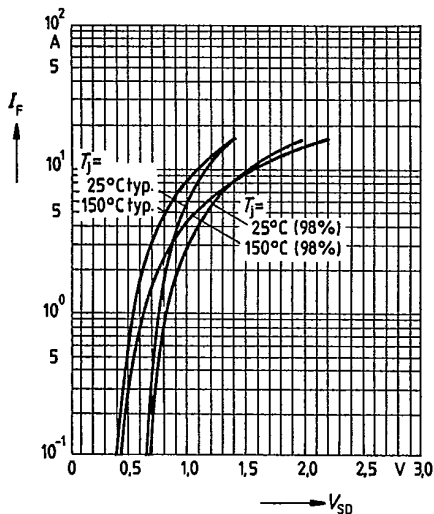
Typical capacitances $C = f(V_{DS})$
 parameter: $V_{GS} = 0$, $f = 1\text{MHz}$



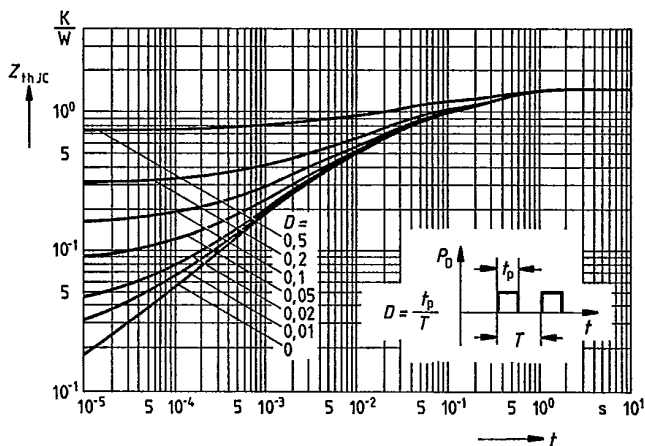
Continuous drain current $I_D = f(T_C)$
 parameter: $V_{GS} \geq 10\text{V}$



Forward characteristic of reverse diode
 $I_F = f(V_{SD})$
 parameter: $T_i, t_p = 80 \mu\text{s}$
 (spread)



Transient thermal impedance $Z_{thJC} = f(t)$
 parameter: $D = t_p / T$



Typical gate-charge $V_{GS} = f(Q_{Gate})$
 parameter: $I_{D\ puls} = 8.0A$

